

## CONTENTS

CONTRIBUTORS TO VOLUME 47 . . . . .	vii
FOREWORD . . . . .	ix

### **Ion Beam Technology Applied to Electron Microscopy** J. FRANKS

I. Introduction . . . . .	1
II. Production of Ion Beams . . . . .	2
III. The Sputtering Process . . . . .	13
IV. Ion Thinning for Transmission Electron Microscopy . . . . .	30
V. Ion Erosion for Scanning Electron Microscopy . . . . .	45
VI. Conclusion . . . . .	47
References . . . . .	48

### **Microprocessors and Their Use in Physics** ANTHONY J. DAVIES

I. Introduction . . . . .	51
II. The Technology of LSI Circuits . . . . .	54
III. The Architecture of Microprocessors . . . . .	61
IV. Memory and Peripheral Devices . . . . .	75
V. Software . . . . .	83
VI. Linking the Experiment to the Microprocessor . . . . .	88
VII. Typical Applications . . . . .	100
VIII. Current and Future Trends . . . . .	109
Appendix I . . . . .	111
Appendix II . . . . .	117
References . . . . .	118
Bibliography . . . . .	118

### **Wire Antennas** P. A. RAMSDALE

I. Introduction . . . . .	123
II. Analysis . . . . .	124
III. Unloaded Antennas . . . . .	152
IV. Passive Loaded Antennas . . . . .	163
V. Active Antennas . . . . .	172
VI. Antenna Selection . . . . .	187
VII. Concluding Remarks . . . . .	192
References . . . . .	192

**Characterization of the MOSFET Operating  
in Weak Inversion**

PAUL A. MULS, GILBERT J. DECLERCK,  
AND ROGER J. VAN OVERSTRAETEN

I.	Introduction . . . . .	197
II.	Accurate Model for the Drain Current in a MOSFET . . . . .	201
III.	Determination of the Surface State Density from Drain Current vs Drain Voltage Measurements in Weak Inversion . . . . .	224
IV.	Influence of Potential Fluctuations on the Mobility in Weak Inversion . . . . .	241
V.	General Conclusion . . . . .	262
	References . . . . .	265

**Modeling of the Transient Response of  
an MIS Capacitor**

T. W. COLLINS, J. N. CHURCHILL, F. E. HOLMSTROM,  
AND A. MOSCHWITZER

I.	Introduction . . . . .	267
II.	Dynamic Equations . . . . .	270
III.	Simplest-Case Example . . . . .	274
IV.	Computer Simulation: Flatband to Inversion Transient for MIS Structure . . . . .	279
V.	Results . . . . .	282
VI.	Examples . . . . .	317
VII.	Conclusion . . . . .	325
	List of Symbols . . . . .	326
	Reverences . . . . .	328
	AUTHOR INDEX . . . . .	331
	SUBJECT INDEX . . . . .	338